

**A two-and-a-half-layer sandwich: potassium
salt of anionic
(η^4 -tetrasilacyclobutadiene)(η^5 -cyclopenta-
dienyl)ruthenium**

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SUPPORTING INFORMATION

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General Procedures.

All experiments were performed using high-vacuum line techniques or in an argon atmosphere using MBRAUN MB 150B-G glove box. All solvents were dried and degassed over potassium mirror in vacuum prior to use. NMR spectra were recorded on Bruker AC-300FT NMR (^1H NMR at 300.1 MHz; ^{13}C NMR at 75.5 MHz; ^{29}Si NMR at 59.6 MHz) and AV-400FT NMR (^1H NMR at 400 MHz; ^{13}C NMR at 100.6 MHz; ^{29}Si NMR at 79.5 MHz) spectrometers. The dipotassium salt of the tetrasilacyclobutadiene dianion $\mathbf{2}^{2-}\cdot[\text{K}^+(\text{thf})_2]_2$ and ruthenium complex $[\text{Cp}^*\text{RuCl}]_4$ were prepared according to the published procedures [1] and [2], respectively.

Experimental Procedure and Spectral Data for $\{\{\eta^4\text{-(}^t\text{Bu}_2\text{MeSi)}_4\text{Si}_4\}\text{RuCp}^*\}^-\cdot[\text{K}^+(\text{thf})_2]_2$ ($\mathbf{1}^-\cdot[\text{K}^+(\text{thf})_2]$).

The dipotassium salt of the tetrasilacyclobutadiene dianion $\mathbf{2}^{2-}\cdot[\text{K}^+(\text{thf})_2]_2$ (125 mg, 0.113 mmol) and $[\text{Cp}^*\text{RuCl}]_4$ (31 mg, 0.029 mmol) were placed in a reaction tube with a magnetic stirring bar. Dry oxygen-free THF (2 ml) was introduced into this tube by vacuum transfer, and the reaction mixture was stirred at room temperature to give a red solution within 1 h. After evaporation of the solvent and removal of the inorganic salt, the reaction mixture was recrystallized from hexane–THF to give $\mathbf{1}^-\cdot[\text{K}^+(\text{thf})_2]$ (85 mg, 65%) as air- and moisture-sensitive red crystals. Mp > 300 °C (dec.); ^1H NMR (THF- d_8 , δ) 0.04 (s, 12 H, CH_3), 1.14 (s, 72 H, $\text{C}(\text{CH}_3)_3$), 2.28 (s, 15 H, $(\text{CH}_3)_5\text{C}_5$); ^{13}C NMR (THF- d_8 , δ) –2.7 (CH_3), 16.1 ($(\text{CH}_3)_5\text{C}_5$), 22.0 ($\text{C}(\text{CH}_3)_3$), 32.0 ($\text{C}(\text{CH}_3)_3$), 88.6 ($(\text{CH}_3)_5\text{C}_5$); ^{29}Si NMR (THF- d_8 , δ) –49.8 (skeletal Si), 20.4 (substituent Si).

X-ray Diffraction Study and Crystallographic Data for $\mathbf{1}^-\cdot[\text{K}^+(\text{thf})_2]$.

The single crystals of $\mathbf{1}^-\cdot[\text{K}^+(\text{thf})_2]$ for X-ray diffraction analysis were grown from a hexane–THF solution at –30 °C. Diffraction data were collected at 150 K on a MacScience DIP2030 Image Plate diffractometer equipped with a rotating anode (50 kV, 90 mA) employing graphite-monochromatized Mo- $K\alpha$ radiation ($\lambda = 0.71070$ Å). The structure was solved by the direct method using SIR-92 [3] program and refined by the full-matrix least-squares method by SHELXL-97 program [4]. Crystallographic data for $\mathbf{1}^-\cdot[\text{K}^+(\text{thf})_2]$ at 150 K: MF = $\text{C}_{54}\text{H}_{115}\text{K}_1\text{O}_2\text{Ru}_1\text{Si}_8$, MW = 1161.35, orthorhombic, *Pccn*,

$a = 20.5640(5)$, $b = 44.9360(4)$, $c = 14.2880(13)$ Å, $V = 13203.0(12)$ Å³, $Z = 8$, $D_{\text{calcd}} = 1.169$ g•cm⁻³. The final R factor was 0.0639 for 9512 reflections with $I_0 > 2\sigma(I_0)$ ($R_w = 0.1697$ for all data, 14892 reflections) with $I > 2\sigma(I)$, GOF = 1.019. CCDC-764194 contains the supplementary crystallographic data for this paper. These data can be obtained free of charge from The Cambridge Crystallographic Data Centre via www.ccdc.cam.ac.uk/data_request/cif.

References:

- [1] V. Ya. Lee, K. Takanashi, T. Matsuno, M. Ichinohe, A. Sekiguchi, *J. Am. Chem. Soc.*, 2004, **126**, 4758.
- [2] P. J. Fagan, M. D. Ward, J. V. Caspar, J. C. Calabrese, P. J. Krusic, *J. Am. Chem. Soc.*, 1988, **110**, 2981.
- [3] A. Altomare, G. Cascarano, C. Giacovazzo, A. Guagliardi, M. C. Burla, G. Polidori, M. Camalli, *J. Appl. Crystallogr.*, 1994, **27**, 435.
- [4] G. M. Sheldrick, SHELXL-97, *Program for Crystal Structure Refinement*, University of Göttingen, Germany, 1997.